

Special Issue on Selected Articles from the Proceedings of the 2004 Denver X-ray Conference

In early 2003, *Powder Diffraction* and the Denver X-ray Conference agreed to collaborate on publishing the advance program of upcoming Denver X-ray Conferences and selected articles from the proceedings of the Denver X-ray Conference, *Advances in X-ray Analysis*, in *Powder Diffraction*. So far, the collaboration has led to the advance publication of the 2003 and 2004 programs of the Denver X-ray Conference in the June 2003 and 2004 issues of *Powder Diffraction*. In addition, twenty high-quality articles from Volume 47 of *Advances in X-ray Analysis* were published in the March 2004 issue of *Powder Diffraction*. The CD-ROM of Volume 47 of *Advances in X-ray Analysis* has also been distributed to each institutional print or print/online subscriber of *Powder Diffraction*. This collaboration has significantly increased services and the number of technical articles available to *Powder Diffraction* subscribers, as well as circulation for the authors of *Advances in X-ray Analysis*.

Since this collaboration has received many positive responses from our X-ray analysis community, *Powder Diffraction* will continue to publish annually both the advance program and selected articles from the proceedings of the Denver X-ray Conference in the June issue of *Powder Diffraction*.

This special June 2005 issue of *Powder Diffraction* is dedicated to the high-quality articles from the 2004 Denver X-ray Conference and the advance program for the upcoming

2005 Denver X-ray Conference to be held 1–5 August 2005 at Colorado Springs, Colorado. The 2004 Denver X-ray Conference attracted more than 500 attendees and exhibit personnel from around the world. Over forty of the nearly 200 X-ray diffraction and fluorescence papers presented at the conference have been accepted for publication in Volume 48 of *Advances in X-ray Analysis*. Twenty of the proceedings papers have been selected by the editors of *Advances in X-ray Analysis* for publication in this special June 2005 issue of *Powder Diffraction*. The CD-ROM of Volume 48 of *Advances in X-ray Analysis* will be ready for distribution soon.

It is our hope that our readers will enjoy these articles and learn more about X-ray diffraction and fluorescence activities conducted by our colleagues around the world. Finally I want to thank Drs. Victor Buhrke, John Gilfrich, George Havrilla, James Kaduk, Cev Noyan, and Robert Snyder of the Denver X-ray Conference Organizing committee for their selections and editing of the articles that appear in this issue. I also thank my assistant Allen Huang and Cathyan Colaiezzi, Managing Editor, for making sure everything was in place for this June publication. And a special thanks to the authors for their outstanding contributions to this issue.

Ting C. Huang
Editor-in-Chief